


Issue Classification 	Application No.	Applicant(s)	
	09/652,735	AUNE, LEIF EINAR	
	Examiner	Art Unit	
	Philip C Lee	2154	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS	SUBCLASS				CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
709	228				709	228	222	245	
INTERNATIONAL CLASSIFICATION					370	401	313	338	
G	0	6	F	15/177					
G	0	6	F	15/16					
H	0	4	L	12/28					
H	0	4	Q	7/00					
H	0	4	Q	7/24					

<i>Philip Lee</i> 2/2/05 (Assistant Examiner) (Date)	<i>John Follansbee</i> SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100 (Primary Examiner) (Date)	Total Claims Allowed: 7 O.G. Print Claim(s) 1 O.G. Print Fig. 2
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<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
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	2		32		62		92		122		152		182		
	3		33		63		93		123		153		183		
	4		34		64		94		124		154		184		
	5		35		65		95		125		155		185		
	6		36		66		96		126		156		186		
	7		37		67		97		127		157		187		
	8		38		68		98		128		158		188		
	9		39		69		99		129		159		189		
	10		40		70		100		130		160		190		
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2	12		42		72		102		132		162		192		
3	13		43		73		103		133		163		193		
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6	16		46		76		106		136		166		196		
	17		47		77		107		137		167		197		
7	18		48		78		108		138		168		198		
	19		49		79		109		139		169		199		
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	21		51		81		111		141		171		201		
	22		52		82		112		142		172		202		
	23		53		83		113		143		173		203		
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	25		55		85		115		145		175		205		
	26		56		86		116		146		176		206		
	27		57		87		117		147		177		207		
	28		58		88		118		148		178		208		
	29		59		89		119		149		179		209		
	30		60		90		120		150		180		210		